

<b>Notice of References Cited</b>	Application/Control No. 09/973,302	Applicant(s)/Patent Under Reexamination CHAIKO, DAVID J.	
	Examiner Katarzyna Wyrozebski Lee	Art Unit 1714	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,555,610	04-2003	Blanton et al.	524/445
	B	US-6,172,121	01-2001	Chaiko	516/101
	C	US-6,521,678	02-2003	Chaiko	523/333
	D	US-5,552,469	09-1996	Beall et al.	524/445
	E	US-6,034,163	03-2000	Barbee et al.	524/445
	F	US-6,403,231	06-2002	Mueller et al.	428/474.4
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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